

STD60NH03L STD60NH03L-1

N-channel 30V - 0.0075Ω - 60A - DPAK/IPAK STripFETTM III Power MOSFET

General features

Туре	V _{DSS}	R _{DS(on)}	I _D
STD60NH03L-1	30V	<0.009Ω	60A
STD60NH03L	30V	<0.009Ω	60A

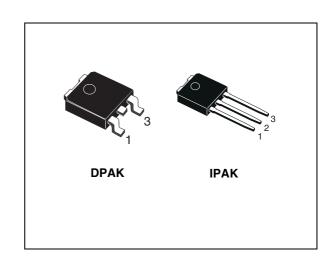
- lacksquare R_{DS(ON)} x Q_g industry's benchmark
- Conduction losses reduced
- Switching losses reduced
- Low threshold device

Description

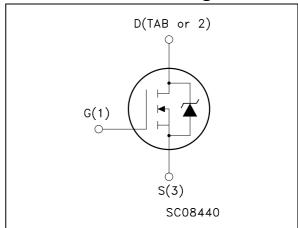
The device utilizes the latest advanced design rules of ST's proprietary STripFET™ technology. This is suitable for the most demanding DC-DC converter application where high efficiency is to be achieved.e of paramount importance.

Applications

■ Switching application



Internal schematic diagram



Order codes

Part number	Marking	Package	Packaging
STD60NH03LT4	D60NH03L	DPAK	Tape & reel
STD60NH03L-1	D60NH03L	IPAK	Tube

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1 Electrical ratings

Table 1. Absolute maximum ratings

Symbol	Parameter	Value	Unit	
V _{DS}	Drain-source voltage (V _{GS} = 0)	30	V	
V _{DGR}	Drain-gate voltage ($R_{GS} = 20 \text{ k}\Omega$)	30	V	
V _{GS}	Gate- source voltage	± 20	V	
I _D	Drain current (continuous) at T _C = 25°C	60	Α	
I _D	Drain current (continuous) at T _C = 100°C	43	Α	
I _{DM} ⁽¹⁾	Drain current (pulsed)	240	Α	
P _{tot}	Total dissipation at T _C = 25°C	70	W	
	Derating factor	0.47	W/°C	
E _{AS} ⁽²⁾	Single pulse avalanche energy	300	mJ	
T _{stg}	Storage temperature	-55 to 175	°C	
T _j	Max. operating junction temperature			

^{1.} Pulse width limited by safe operating area.

Table 2. Thermal data

Rthj-case	Thermal resistance junction-case max	2.14	°C/W
Rthj-amb	Thermal resistance junction-to ambient max	100	°C/W
Rthj-pcb ⁽¹⁾	Thermal resistance junction-to pcb max	43	°C/W
T _J	Maximum lead temperature for soldering purpose	275	°C

^{1.} When mounted on minimum foot-print

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^{2.} Starting Tj=25°C, I_D =30A, V_{DD} =20V

2 Electrical characteristics

(T_{CASE}=25°C unless otherwise specified)

Table 3. On/off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	$I_D = 250 \mu A, V_{GS} = 0$	30			V
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	V_{DS} = Max rating V_{DS} = Max rating, T_{C} = 125°C			1 10	μ Α μ Α
I _{GSS}	Gate-body leakage current (V _{DS} = 0)	V _{GS} = ± 20V			±100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1			V
R _{DS(on)}	Static drain-source on resistance	$V_{GS} = 10V, I_D = 30A$ $V_{GS} = 5V, I_D = 30A$		0.0075 0.009	0.009 0.017	Ω

Table 4. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
9 _{fs} ⁽¹⁾	Forward transconductance	V _{DS} = 15V, I _D = 18A		25		S
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	$V_{DS} = 25V, f = 1MHz,$ $V_{GS} = 0$		2200 380 49		pF pF pF
R _G	Gate input resistance	f=1 MHz Gate DC Bias = 0 Test Signal Level = 20mV Open Drain		1.5		Ω
t _{d(on)} t _r t _{d(off)}	Turn-on delay time Rise time Turn-off delay time Fall time	V_{DD} = 15V, I_D = 30A R_G = 4.7 Ω V_{GS} = 5V (see <i>Figure 13</i>)		21 95 19 15		ns ns ns
Q _g Q _{gs} Q _{gd}	Total gate charge Gate-source charge Gate-drain charge	V_{DD} = 15V, I_D = 60A, V_{GS} = 5V, R_G = 4.7 Ω (see <i>Figure 14</i>)		15.7 8.3 3.4	21	nC nC nC
Q _{gls} ⁽²⁾	Third-quadrant gate charge	$V_{DS} < 0 \text{ V}, V_{GS} = 10 \text{ V},$ $I_{D} = 60 \text{ A}$		15		nC

^{1.} Pulsed: Pulse duration = 300 μs, duty cycle 1.5 %.

^{2.} Gate charge for syncronous operation. See Chapter 4: Appendix A

Table 5. Source drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD}	Source-drain current Source-drain current (pulsed)				60 240	A A
V _{SD} ⁽²⁾	Forward on voltage	I _{SD} = 30A, V _{GS} = 0			1.3	V
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	I_{SD} = 60A, di/dt = 100A/ μ s, V_{DD} = 20V, T_j = 150°C (see <i>Figure 15</i>)		32 51 3.2		ns nC A

^{1.} Pulse width limited by safe operating area.

^{2.} Pulsed: Pulse duration = 300 μ s, duty cycle 1.5 %

2.1 Electrical characteristics (curves)

Figure 1. Safe operating area

Figure 2. Thermal impedance

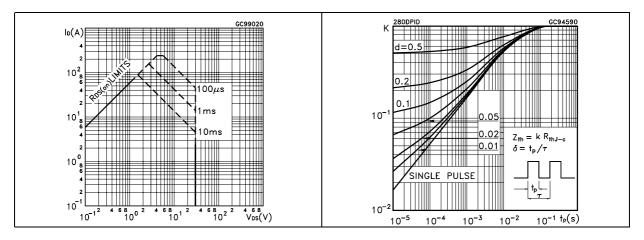


Figure 3. Output characterisics

Figure 4. Transfer characteristics

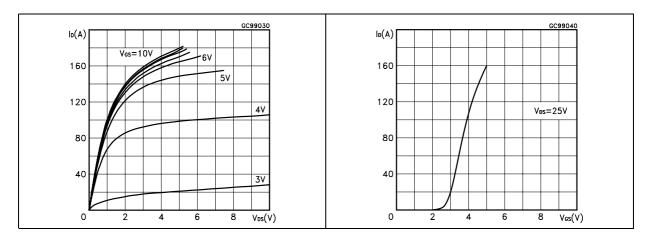


Figure 5. Transconductance

Figure 6. Static drain-source on resistance

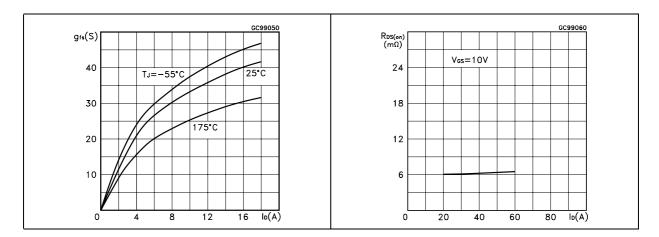


Figure 7. Gate charge vs gate-source voltage Figure 8. Capacitance variations

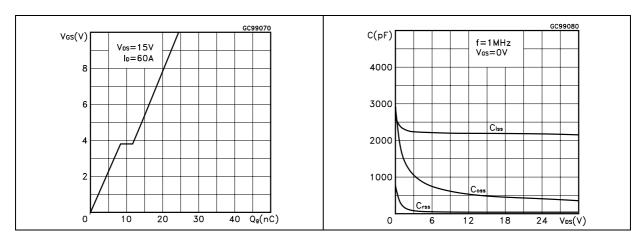


Figure 9. Normalized gate threshold voltage vs temperature

Figure 10. Normalized on resistance vs temperature

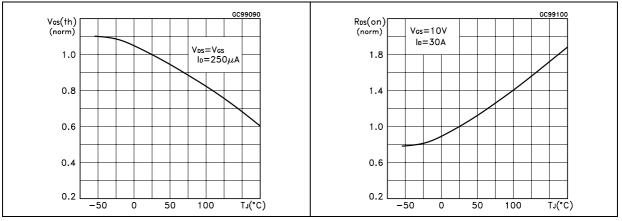
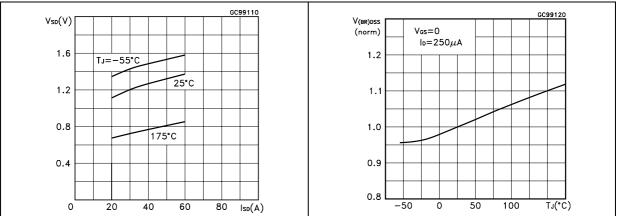


Figure 11. Source-drain diode forward characteristics

Figure 12. Normalized breakdown voltage vs temperature



3 Test circuit

Figure 13. Switching times test circuit for resistive load

Figure 14. Gate charge test circuit

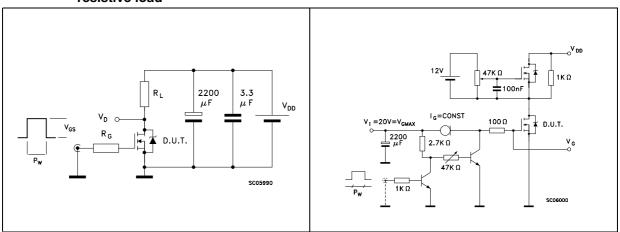


Figure 15. Test circuit for inductive load switching and diode recovery times

Figure 16. Unclamped Inductive load test circuit

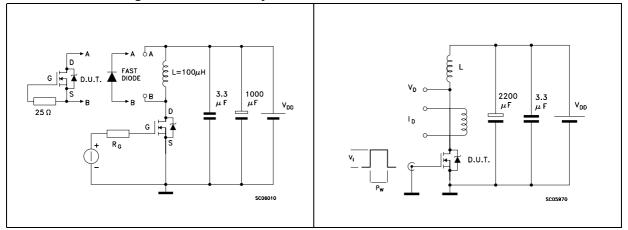
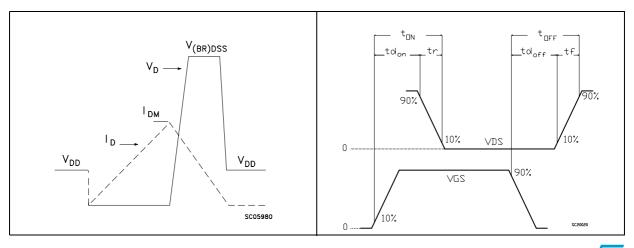


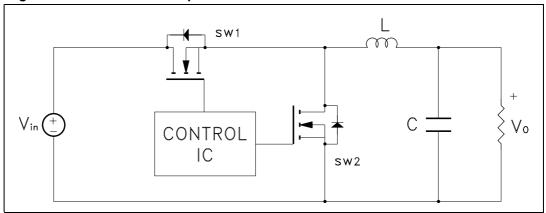
Figure 17. Unclamped inductive waveform

Figure 18. Switching time waveform



4 Appendix A

Figure 19. Buck converter: power losses estimation



The power losses associated with the FETs in a synchronous buck converter can be estimated using the equations shown in the table below. The formulas give a good approximation, for the sake of performance comparison, of how different pairs of devices affect the converter efficiency. However a very important parameter, the working temperature, is not considered. The real device behavior is really dependent on how the heat generated inside the devices is removed to allow for a safer working junction temperature.

- The low side (SW2) device requires:
- Very low R_{DS(on)} to reduce conduction losses
- Small Qgls to reduce the gate charge losses
- Small Coss to reduce losses due to output capacitance
- Small Qrr to reduce losses on SW1 during its turn-on
- The Cgd/Cgs ratio lower than Vth/Vgg ratio especially with low drain to source
- voltage to avoid the cross conduction phenomenon;
- The high side (SW1) device requires:
- Small Rg and Ls to allow higher gate current peak and to limit the voltage feedback on the gate
- Small Qg to have a faster commutation and to reduce gate charge losses
- Low R_{DS(on)} to reduce the conduction losses.

Table 6. Power losses calculation

	High side switching (SW1)	Low side switch (SW2)
Pconduction	$R_{_{\mathrm{DS(on)SW1}}}*I_{_{\mathrm{L}}}^{2}*\delta$	$R_{DS(on)SW2} * I_L^2 * (1 - \delta)$
Pswitching	$V_{\text{in}} * (Q_{\text{gsth(SW1)}} + Q_{\text{gd(SW1)}}) * f * \frac{I_L}{I_g}$	Zero Voltage Switching

Table 6. Power losses calculation

		High side switching (SW1)	Low side switch (SW2)
Pdiode	Recovery (1)	Not applicable	$V_{in} *Q_{rr(SW2)} *f$
1 diode	Conductio n	Not applicable	$V_{f(SW2)} * I_L * t_{deadtime} * f$
Pgate	e(Q _G)	$Q_{g(SW1)} * V_{gg} * f$	$Q_{gls(SW2)} *V_{gg} *f$
P _{Qoss}		$\frac{V_{in} *Q_{oss(SW1)} *f}{2}$	$\frac{V_{in} *Q_{oss(SW2)} *f}{2}$

^{1.} Dissipated by SW1 during turn-on

Table 7. Paramiters meaning

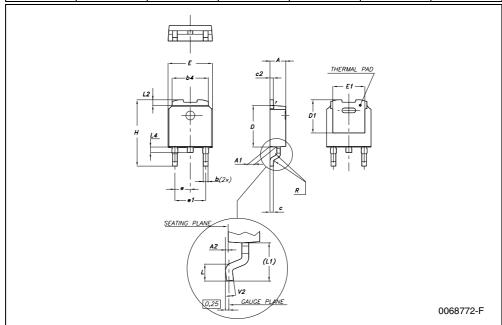
Parameter	Meaning			
d	Duty-cycle			
Q _{gsth}	Post threshold gate charge			
Q _{gls}	Third quadrant gate charge			
Pconduction	On state losses			
Pswitching	On-off transition losses			
Pdiode	Conduction and reverse recovery diode losses			
Pgate	Gate drive losses			
P _{Qoss}	Output capacitance losses			

5 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect . The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: www.st.com

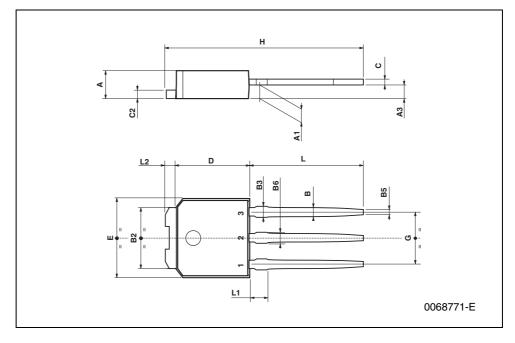
DPAK MECHANICAL DATA

		mm.			inch	
DIM.		111111.			IIICII	1
	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
Α	2.2		2.4	0.086		0.094
A1	0.9		1.1	0.035		0.043
A2	0.03		0.23	0.001		0.009
В	0.64		0.9	0.025		0.035
b4	5.2		5.4	0.204		0.212
С	0.45		0.6	0.017		0.023
C2	0.48		0.6	0.019		0.023
D	6		6.2	0.236		0.244
D1		5.1			0.200	
E	6.4		6.6	0.252		0.260
E1		4.7			0.185	
е		2.28			0.090	
e1	4.4		4.6	0.173		0.181
Н	9.35		10.1	0.368		0.397
L	1			0.039		
(L1)		2.8			0.110	
L2		0.8			0.031	
L4	0.6		1	0.023		0.039
R		0.2			0.008	
V2	0°		8°	0°		8°



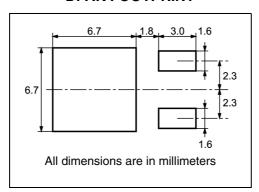
TO-251 (IPAK) MECHANICAL DATA

DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
Α	2.2		2.4	0.086		0.094
A1	0.9		1.1	0.035		0.043
А3	0.7		1.3	0.027		0.051
В	0.64		0.9	0.025		0.031
B2	5.2		5.4	0.204		0.212
В3			0.85			0.033
B5		0.3			0.012	
B6			0.95			0.037
С	0.45		0.6	0.017		0.023
C2	0.48		0.6	0.019		0.023
D	6		6.2	0.236		0.244
E	6.4		6.6	0.252		0.260
G	4.4		4.6	0.173		0.181
Н	15.9		16.3	0.626		0.641
L	9		9.4	0.354		0.370
L1	0.8		1.2	0.031		0.047
L2		0.8	1		0.031	0.039

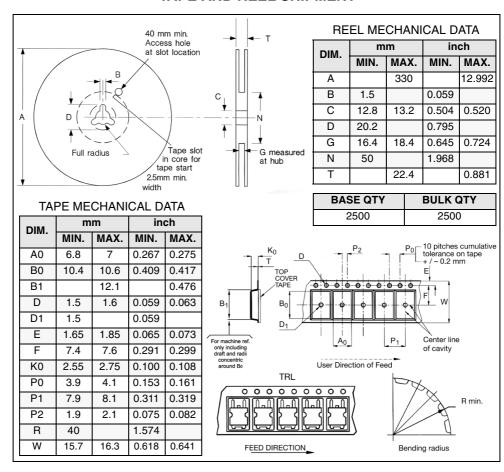


6 Packing mechanical data

DPAK FOOTPRINT



TAPE AND REEL SHIPMENT



7 Revision history

Table 8. Revision history

Date	Revision	Changes
21-Jun-2004	5	Preliminary version
19-Jul-2006	6	New template, no content change

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